



500.39826CX1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: KANNO, et al.
Serial No.: 10/679,342
Filed: October 7, 2003
For: SEMICONDUCTOR MANUFACTURING APPARATUS
AND METHOD OF PROCESSING SEMICONDUCTOR
WAFER USING PLASMA, AND WAFER VOLTAGE
PROBE
Group: 1763
Examiner: unknown

INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR 1.97 & 1.98

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

July 11, 2005

Sir:

In the matter of the above-identified application, applicant(s) are submitting herewith a copy of a communication from a foreign patent office in a counterpart foreign application and copies of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

This information disclosure statement is being submitted before the mailing date of a first office action on the merits.

To the extent the documents listed on the attached form equivalent to Form PTO-1449 are not in the English language, the requirement of 37 CFR 1.98(a)(3) for a concise explanation of the relevance is satisfied by an English language version or translation of the foreign patent office report citing the

documents.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Antonelli, Terry, Stout & Kraus, LLP, Deposit Account No. 01-2135 (Case No. 500.39826CX1), and please credit any excess fees to such deposit account.

Respectfully submitted,

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PJS/slk
Enclosures

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DKT. NO.
500.39826CX1SERIAL NO.
10/679,342INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

(Use several sheets if necessary)

APPLICANT
KANNO, et al.FILING DATE
October 7, 2003GROUP
1763

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
	AA					
	AB					
	AC					
	AD					
	AE					
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	AH					
	AI					
	AJ					
	AK					
	AL					

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation /Abstract	
						Yes	No
	AM	9-129594	5-16-97	Japan		X	
	AN						
	AO						
	AP						
	AQ						
	AR						
	AS						
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	AU	
	AV	
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Examiner		Date Considered

